

# **PRODUCT/PROCESS CHANGE NOTICE (PCN)**

PCN #: A1402-04	DATE: 22-May-2014	MEANS OF DISTIN	GUISHING CHA	NGED DEVICES:
Product Affected: VFQFPN-20, VFQFPN-24 Refer to Attachment II for the affected part numbers		<ul> <li>Product Mark</li> <li>Back Mark</li> <li>Date Code</li> <li>Other</li> </ul>		
Date Effective: 22-Aug-2014				
Contact: IDT PCN DESK E-mail: pcndesk@idt.com		Attachment: Please com Samples: Please com sample req		No No
DESCRIPTION AND PURPOSE OF CH	IANGE:			
Die TechnologyThis notification is to advise our customers that IDT is adding ASE Chungli, TaiwWafer Fabrication Process(ASECL) as alternate Assembly and Test facilities.Assembly ProcessThere is no change to the moisture performance.			SE Chungli, Taiwan	
<ul> <li>Material</li> <li>Testing</li> <li>Manufacturing Site</li> <li>Data Sheet</li> <li>Other</li> </ul>	Attachment I details the qualification data for this change and Attachment II shows the affected list of part numbers.			
<b>RELIABILITY/QUALIFICATION SUM</b> Refer to qualification data shown in Attach				
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.				
Customer:	C	Approval for sl	hipments prior	to effective date.
Name/Date:	ne/Date: E-Mail Address:			
Title:	Phone# /Fax# :			
CUSTOMER COMMENTS:				
IDT ACKNOWLEDGMENT OF RECE	IPT:			
RECD. BY:		DATE:		_



## **PRODUCT/PROCESS CHANGE NOTICE (PCN)**

### **ATTACHMENT I - PCN # : A1402-04**

PCN Type:	Manufacturing Site - Alternate Assembly & Test Location		
Data Sheet Change:	None		
	No change in moisture sensitivity level (MSL)		

#### **Detail Of Change:**

This notification is to advise our customers that IDT is adding ASE Chungli, Taiwan (ASECL) as alternate Assembly and Test facilities. Presently, ASECL is a qualified IDT Subcontractors.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

The material set details of the current and alternate assembly location is as shown in Table 2. The die attach and mold compound used at the alternate assembly are qualified IDT materials. There is no change from the existing qualified lead frame material, lead finish, and wire for the alternate assembly location.

There is no change to the moisture performance.

There is also no change in the Test processing flows. Testers, load boards and test programs are compatible at the qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

Table 1: The Existing and Alternate Assembly & Test Locations

	Existing Assembly & Test	Alternate Assembly & Test
Package	ATK - Amkor, Korea	ASECL - ASE, Taiwan
VFQFPN-20 VFQFPN-24	Х	Х

Note: X denote qualified assembly & test location

#### Table 2: Assembly Material Sets for The Existing and Alternate Assembly Locations

	Existing Assembly	Alternate Assembly	
Material Set / Assembly	ATK - Amkor, Korea	ASECL - ASE, Taiwan	
Die Attach	CRM1085A	EN4900	
Wire	PdCu wire	PdCu wire	
Mold Compound	G700, G631BQF	G700 LA	



## **PRODUCT/PROCESS CHANGE NOTICE (PCN)**

### ATTACHMENT I - PCN # : A1402-04

#### **Qualification Information and Qualification Data:** <u>Part I - Assembly Qual Results</u>

- Affected Packages: VFQFPN-20, VFQFPN-24
- Assembly Material: The affected package type is using ASECL standard materials shown on page 2 of this attachment.
- Qual Plan & Results: Tests are in accordance with JEDEC47 recommended tests.

Qualification Vehicle: VFQFPN-20 (1 lot)

Test Description	Test Method	Test Results (Rej / SS)
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0/30
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0/30
High Temperature Storage Test (150°C, 1000 hours)	JESD22-A103	0/30

Tests were subjected to Preconditioning per JESD22-A113 prior to stress test



## **PRODUCT/PROCESS CHANGE NOTICE (PCN)**

### **ATTACHMENT I - PCN # : A1402-04**

#### **Qualification Information and Qualification Data:** <u>Part II - Electrical Test Correlation Results</u>

Vehicle:F1950NBGISample size:496 electrically good units and 10 reject units

Description	Existing Test (ATK - Amkor, Korea)	Alternate Test (ASECL - ASE, Taiwan)	
Tester Platform	Catalyst	Catalyst	
Loadboard	F1950	F1950	
Test Program	IDT1950_08	IDT1950_09 <sup>1</sup>	
Test Site	Dual site	Dual site	
Test Temperature	Ambient	Ambient	
Test Correlation Results	100%	100%	
Number of Good Units Correlated @ ambient	496 pcs	496 pcs	
496 units Bin 1 handler run (good units)	Passed	Passed	
Number of Reject Units Correlated @ ambient	10 pcs	10 pcs	
10 units rejects handler run	Passed	Passed	
496 units Bin 1 datalog correlation (good units)	Passed	Passed	
10 units rejects datalog correlation	Passed	Passed	

*Note:* <sup>1</sup>*Revision 09 was removed T3000 to T3014. These tests should not be included in the final production test. They were included originally just for data collection purposes.* 



## **PRODUCT/PROCESS CHANGE NOTICE (PCN)**

### ATTACHMENT II - PCN # : A1402-04

#### **Affected Part Numbers**

Part Number	Part Number	Part Number	Part Number
F1701NBGI	F1751NBGI8	F1950NBGI	F1951NBGI8
F1701NBGI8	F1763NBGI	F1950NBGI8	F1953NCGI
F1751NBGI	F1763NBGI8	F1951NBGI	F1953NCGI8